

A

- Ahmad I.** – See Elgomati H.A., Salehuddin F., Hamid F.A., Zaharim A., Majlis B.Y., Apté P.R.; **14(2)**, 145-151.
- Ait A.O.** – See Kobeleva O.I., Valova T.M., Barachevsky V.A., Grytsenko K.P., Machulin V.F., Krayushkin M.M.; **14(4)**, 441-444.
- Akinlami J.O.** – Photoemission study of the electronic structure of praseodymium filled skutterudite ($\text{PrOs}_4\text{Sb}_{12}$) – Awobode A.M.; **14(2)**, 237-240.
- Alekseev S.A.** – See Manilov A.I., Skryshevsky V.A., Kuznetsov G.V.; **14(1)**, 1-6.
- Aleshkevych P.** – See Lashkarev G.V. Sichkovskiy V.I., Radchenko M.V., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A., Nedelko N., Yakiela R., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14(3)**, 263-268.
- Aliakbari N.** – See Javidi S., Enayati R., Iraj M.; **14(2)**, 175-182.
- Alyakshev I.P.** – See Kozubovsky V.R., Kormosh V.V., Lishchenko N.H.; **14(3)**, 330-333.
- Amer H.H.** – Characterization of quaternary chalcogenide As-Ge-Te-Si thin films – Elkordy M., Zien M., Dahshan A., Elshamy R.A.; **14(3)**, 302-307.
- Androsyuk I.G.** – See Lysiuk V.O., Staschuk V.S., Moskalenko N.L.; **14(1)**, 59-61.
- Angelsky A.P.** – See Ushenko Yu.A.; **14(1)**, 41-50.
- Angelsky O.P.** – See Ushenko Yu.O., Balanetska V.O.; **14(3)**, 365-374.
- Aoki T.** – See Kosyachenko L.A., Rarenko I.M., Sklyarchuk V.M., Maslyanchuk O.L., Yurtsenyuk N.S., Zakharuk Z.I.; **14(4)**, 421-426.
- Apte P.R.** – See Elgomati H.A., Ahmad I., Salehuddin F., Hamid F.A., Zaharim A., Majlis B.Y.; **14(2)**, 145-151.
- Avksentyeva L.** – See Khrypunov G., Meriuts A., Shelest T., Deineko N., Klyui N., Gorbulik V.; **14(3)**, 308-312.
- Avksentyeva L.V.** – See Khrypunov G.S., Shelest T.N., Li T.N., Meriuts A.V., Kovtun N.A., Makarov A.V.; **14(1)**, 122-126.
- Avramenko K.A.** – See Strelchuk V.V., Bryksa V.P., Lytvyn P.M., Valakh M.Ya., Pashchenko V.O., Bludov O.M., Deparis C., Morhain C., Tronc P.; **14(1)**, 31-40.
- Awobode A.M.** – Akinlami J.O.; **14(2)**, 237-240.

B

- Balagurov A.M.** – See Lashkarev G.V. Sichkovskiy V.I., Radchenko M.V., Aleshkevych P., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A.,

- Nedelko N., Yakiela R., Beskrovnyy A.I., Dobrowolski W.; **14(3)**, 263-268.
- Balanetska V.O.** – See Ushenko O.G., Zabolotna N.I.; **14(4)**, 403-410.
- Balanetska V.O.** – See Ushenko Yu.O., Angelsky O.P.; **14(3)**, 365-374.
- Balanetska V.O.** – See Zabolotna N.I., Telenga O.Yu., Ushenko V.O.; **14(2)**, 228-236.
- Balanetska V.O.** – Singular analysis of Jones-matrix images describing polycrystalline networks of biological crystals in diagnostics of cholelithiasis in its latent period – Marchuk Yu., Karachevtsev A.V., Ushenko V.O.; **14(2)**, 188-194.
- Balanetskaya V.O.** – See Ushenko Yu.A., Olar O.I., Dubolazov A.V., Unguryan V.P., Oleinichenko N.I., Zabolotna B.P.; **14(1)**, 98-105.
- Barachevsky V.A.** – See Kobeleva O.I., Valova T.M., Ait A.O., Grytsenko K.P., Machulin V.F., Krayushkin M.M.; **14(4)**, 441-444.
- Baschenko S.M.** – On Raman spectra of water, its structure and dependence on temperature – Marchenko L.S.; **14(1)**, 77-79.
- Bataiev Mykola** – Effect of proton irradiation on AlGaN/AlN/GaN HEMTs – Bataiev Yurii, Brillson Leonard; **14(3)**, 279-286.
- Bataiev Mykola** – Effect of proton irradiation on the parameters of AlGaN/GaN HEMTs – Bataiev Yurii, Brillson Leonard; **14(4)**, 381-388.
- Bataiev Yurii** – See Bataiev Mykola, Brillson Leonard; **14(3)**, 279-286.
- Bataiev Yurii** – See Bataiev Mykola, Brillson Leonard; **14(4)**, 381-388.
- Beketov G.V.** – Enhanced 2D plotting method for scanning probe microscopy imaging; **14(1)**, 80-87.
- Belyaev A.E.** – See Kiselov V.S., Lytvyn O.S., Yukhymchuk V.O.; **14(1)**, 7-11.
- Belyaev A.E.** – See Marchylo O.M., Zavyalova L.V., Nakanishi Y., Kominami H., Svechnikov G.S.; **14(4)**, 461-464.
- Belyaev A.E.** – Some aspects of thermal resistance measurement technique for IMPATT and light-emitting diodes – Boltovets N.S., Konakova R.V., Kudryk Ya.Ya., Sorokin V.M., Sheremet V.N., Shynkarenko V.V.; **14(4)**, 465-469.
- Beskrovnyy A.I.** – See Lashkarev G.V. Sichkovskiy V.I., Radchenko M.V., Aleshkevych P., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A., Nedelko N., Yakiela R., Balagurov A.M., Dobrowolski W.; **14(3)**, 263-268.
- Bezbakh I.Zh.** – See Shul'pina I.L., Kyutt R.N., Ratnikov V.V., Prokhorov I.A., Shcheglov M.P.; **14(1)**, 62-70.
- Blonskyi I.** – See Dolgov L., Kravchuk R., Rybak A., Kiisk V., Sildos I.; **14(3)**, 325-329.
- Bludov O.M.** – See Strelchuk V.V., Bryksa V.P., Avramenko K.A., Lytvyn P.M., Valakh M.Ya.,

- Pashchenko V.O., Deparis C., Morhain C., Tronc P.; **14**(1), 31-40.
- Bochkova T.M.** – Charge transport in bismuth orthogermanate crystals – Plyaka S.N.; **14**(2), 170-174.
- Boiko I.I.** – Influence of electron-electron drag on piezoresistance of n-Si; **14**(2), 183-187.
- Boiko I.I.** – Influence of mutual drag of light and heavy holes on conductivity of p-silicon and p-germanium; **14**(3), 357-361.
- Boiko I.I.** – Influence of mutual drag of light and heavy holes on magnetoresistivity and Hall-effect of p-silicon and p-germanium; **14**(4), 437-440.
- Boltovets N.S.** – See Belyaev A.E., Konakova R.V., Kudryk Ya.Ya., Sorokin V.M., Sheremet V.N., Shynkarenko V.V.; **14**(4), 465-469.
- Boltovets P.M.** – Effect of microwave radiation on optical characteristics of thin gold films; **14**(2), 209-212.
- Borblik V.L.** – Negative magnetoresistance of heavily doped silicon p-n junction – Rudnev I.A., Shwarts Yu.M., Shwarts M.M.; **14**(1), 88-90.
- Bortshagovsky E.G.** – See Dvoynenko M.M., Kazantseva Z.I., Strelchuk V.V., Kolomys O.F., Venger E.F., Tronc P.; **14**(2), 195-199.
- Bratus' O.L.** – Structural properties of nanocomposite SiO₂(Si) films obtained by ion-plasma sputtering and thermal annealing – Evtukh A.A., Lytvyn O.S., Voitovich M.V., Yukhymchuk V.O.; **14**(2), 247-255.
- Briksa V.P.** – See Kulish M.R., Struzhko V.L., Murashko A.V., Il'in V.G.; **14**(1), 21-30.
- Brillson Leonard** – See Bataiev Mykola, Bataiev Yurii; **14**(3), 279-286.
- Brillson Leonard** – See Bataiev Mykola, Bataiev Yurii; **14**(4), 381-388.
- Brus V.V.** – Comparison of optical properties of TiO₂ thin films prepared by reactive magnetron sputtering and electron-beam evaporation techniques – Kovalyuk Z.D., Parfen'yuk O.A., Vakhnyak N.D.; **14**(4), 427-431.
- Bryksa V.P.** – See Strelchuk V.V., Avramenko K.A., Lytvyn P.M., Valakh M.Ya., Pashchenko V.O., Bludov O.M., Deparis C., Morhain C., Tronc P.; **14**(1), 31-40.
- Bunak S.V.** – Electrical properties of MIS structures with silicon nanoclusters – Ilchenko V.V., Melnik V.P., Hatsevych I.M., Romanyuk B.N., Shkavro A.G., Tretyak O.V.; **14**(2), 241-246.
- Burbelo R.** – Photo-thermo-acoustic analysis of heterogeneous semiconductor structures under pulse laser irradiation – Isaiev M., Kuzmich A.; **14**(2), 167-169.
- Bushima A.V.** – Information processing in an optoelectronic display system; **14**(2), 222-227.
- Butorin P.E.** – See Lashkarev G.V. Sichkovskiy V.I., Radchenko M.V., Aleshkevych P., Dmitriev

O.I., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A., Nedelko N., Yakiela R., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14**(3), 263-268.

C

Chand Narottam – See Rana Ashwani K., Kapoor

Vinod; **14**(2), 203-208.

Chegel V. – See Lopatynskyi A., Lopatynska O.; **14**(1), 114-121.

Chernenko I.M. – Computer simulation of vanadium dioxide semiconductor phase formation in supersaturated solutions – Mysov O.P., Oleinik O.Yu., Ivon A.I.; **14**(1), 51-54.

D

Dahshan A. – See Amer H.H., Elkordy M., Zien M., Elshamy R.A.; **14**(3), 302-307.

Danilchenko S.M. – See Ivashchenko M.M., Opanasyuk A.S., Opanasyuk N.M., Starikov V.V.; **14**(2), 157-163.

Daskal Ye.M. – See Gudyma Iu.V.; **14**(4), 393-398.

Dauletmuratov B.K. – Features of a shock wave in CdTe by pulsed laser irradiation; **14**(1), 130-134.

Deineko N. – See Khrypunov G., Meriuts A., Shelest T., Klyui N., Avksentyeva L., Gorbulik V.; **14**(3), 308-312.

Denisova Z.L. – See Vlasenko N.A., Oleksenko P.F., Mukhlyo M.O., Lytvyn P.M., Veligura L.I.; **14**(3), 339-343.

Deparis C. – See Strelchuk V.V., Bryksa V.P., Avramenko K.A., Lytvyn P.M., Valakh M.Ya., Pashchenko V.O., Bludov O.M., Morhain C., Tronc P.; **14**(1), 31-40.

Dmitriev O.I. – See Lashkarev G.V. Sichkovskiy V.I., Radchenko M.V., Aleshkevych P., Butorin P.E., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A., Nedelko N., Yakiela R., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14**(3), 263-268.

Dobrovolskiy Yu.G. – Anti-reflection coatings based on SnO₂, SiO₂, Si₃N₄ films for photodiodes operating in ultraviolet and visible spectral ranges – Perevertailo V.L., Shabashkevich B.G.; **14**(3), 298-301.

Dobrowolski W. – See Lashkarev G.V. Sichkovskiy V.I., Radchenko M.V., Aleshkevych P., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A., Nedelko N., Yakiela R., Balagurov A.M., Beskrovnyy A.I.; **14**(3), 263-268.

Dolgolenko A.P. – See Gaidar G.P., Litovchenko P.G.; **14**(2), 213-221.

Dolgolenko A.P. – Seebeck's effect in p-SiGe whisker samples – Druzhinin A.A., Karpenko A.Ya., Nichkalo S.I., Ostrovsky I.P.,

Litovchenko P.G., Litovchenko A.P.; **14**(4), 456-460.

Dolgov L. – Optical properties of the Ti surface structured by femtosecond laser beam – Kravchuk R., Rybak A., Kiisk V., Sildos I., Blonskyi I.; **14**(3), 325-329.
Druzhinin A.A. – See Dolgolenko A.P., Karpenko A.Ya., Nichkalo S.I., Ostrovsky I.P., Litovchenko P.G., Litovchenko A.P.; **14**(4), 456-460.

Dubolazov A.V. – See Ushenko Yu.A., Olar O.I., Balanetskaya V.O., Unguryan V.P., Oleinichenko N.I., Zabolotna B.P.; **14**(1), 98-105.

Dvoynenko M.M. – Probing plasmonic system by the simultaneous measurement of Raman and fluorescence signals of dye molecules – Kazantseva Z.I., Strelchuk V.V., Kolomys O.F., Bortshagovsky E.G., Venger E.F., Tronc P.; **14**(2), 195-199.

E

Elgomati H.A. – Optimal solution in producing 32nm CMOS technology transistor with desired leakage current – Ahmad I., Salehuddin F., Hamid F.A., Zaharim A., Majlis B.Y., Apte P.R.; **14**(2), 145-151.

Elkordy M. – See Amer H.H., Zien M., Dahshan A., Elshamy R.A.; **14**(3), 302-307.

Elshamy R.A. – See Amer H.H., Elkordy M., Zien M., Dahshan A.; **14**(3), 302-307.

Enayati R. – See Javidi S., Iraj M., Aliakbari N.; **14**(2), 175-182.

Evtukh A.A. – See Bratus' O.L., Lytvyn O.S., Voitovych M.V., Yukhymchuk V.O.; **14**(2), 247-255.

F

Fitio V.M. – See Kostyukevych S.O., Muravsky L.I., Voronyak T.I., Shepeliavyi P.E., Kostyukevych K.V., Moskalenko N.L., Pogoda V.I.; **14**(3), 350-356.

Freik D.M. – Size effects in p-PbTe nanostructures on polyamide – Yurchyshyn I.K., Potyak V.Yu., Lysiuk Yu.V.; **14**(3), 344-349.

G

Gaidar G.P. – Changes in Hall parameters after γ -irradiation (^{60}Co) of n-Ge; **14**(3), 294-297.

Gaidar G.P. – The kinetic of point defect transformation during the annealing process in electron-irradiated silicon – Dolgolenko A.P., Litovchenko P.G.; **14**(2), 213-221.

Gamov D.V. – See Oberemok O.S., Litovchenko V.G., Popov V.G., Melnik V.P., Gudymenko

O.Yo., Nikirin V.A., Khatsevich I.M.; **14**(3), 269-272.

Gaponov A.V. – Non-ohmic conduction in tin dioxide based ceramics with copper addition – Glot A.B.; **14**(1), 71-76.

Gavrysh V.I. – Modelling of temperature conditions in the three-dimensional piecewise homogeneous elements of microelectronic devices; **14**(4), 478-481.

Glot A.B. – See Gaponov A.V.; **14**(1), 71-76.

Gorbulik V. – See Khrypunov G., Meriuts A., Shelest T., Deineko N., Klyui N., Avksentyeva L.; **14**(3), 308-312.

Gorishnyj M.P. – See Vovk V.E., Kovalchuk O.V., Kovalchuk T.M.; **14**(2), 256-260.

Greguš J. – See Studenyak I.P., Izai V.Yu., Stephanovich V.O., Panko V.V., Kúš P., Plecenik A., Zahoran M., Roch T.; **14**(3), 287-293.

Grytsenko K.P. – See Kobeleva O.I., Valova T.M., Ait A.O., Barachevsky V.A., Machulin V.F., Krayushkin M.M.; **14**(4), 441-444.

Gudenko Yu.M. – Lateral drift of photo-generated charge carriers in the p-SiGe/Si heterostructures with quantum wells – Vainberg V.V., Poroshin V.M., Tulupenko V.M.; **14**(3), 375-379.

Gudyma Iu.V. – High-temperature expansion in self-consistent-field theory of spin-crossover compounds – Daskal Ye.M.; **14**(4), 393-398.

Gudymenko O.Yo. – Influence of small miscuts on self-ordered growth of Ge nanoislands – Kladko V.P., Yefanov O.M., Slobodian M.V., Polischuk Yu.S., Krasilnik Z.F., Lobanov D.V., Novikov A.A.; **14**(4), 389-392.

Gudymenko O.Yo. – See Oberemok O.S., Litovchenko V.G., Gamov D.V., Popov V.G., Melnik V.P., Nikirin V.A., Khatsevich I.M.; **14**(3), 269-272.

Gumenjuk-Sichevska J.V. – See Sakhno M.V., Sizov F.F.; **14**(1), 55-58.

H

Hamid F.A. – See Elgomati H.A., Ahmad I., Salehuddin F., Zaharim A., Majlis B.Y., Apte P.R.; **14**(2), 145-151.

Hatsevych I.M. – See Bunak S.V., Ilchenko V.V., Melnik V.P., Romanyuk B.N., Shkavro A.G., Tretyak O.V.; **14**(2), 241-246.

Ignatyeva T.A. – Partial dielectric behavior of the Mo electron spectrum as an effect of Van Hove singularities; **14**(4), 482-488.

I

Il'in V.G. – See Kulish M.R., Struzhko V.L., Briksa V.P., Murashko A.V.; **14**(1), 21-30.

- Ilchenko V.V.** – See Bunak S.V., Melnik V.P., Hatsevych I.M., Romanyuk B.N., Shkavro A.G., Tretyak O.V.; **14**(2), 241-246.
- Indutnyi I.Z.** – See Sopinskyy M.V., Michailovska K.V., Shepeliavy P.E., Tkach V.M.; **14**(3), 273-278.
- Indutnyi I.Z.** – See Lisovskyy I.P., Litovchenko V.G., Zlobin S.O., Voitovych M.V., Khatsevich I.M., Shepeliavy P.E., Kolomys O.F.; **14**(1), 127-129.
- Iraj M.** – See Javidi S., Enayati R., Aliakbari N.; **14**(2), 175-182.
- Isaiev M.** – See Burbelo R., Kuzmich A.; **14**(2), 167-169.
- Ivashchenko M.M.** – Structural and optical characteristics of ZnSe and CdSe films condensed on non-oriented substrates – Opanasyuk A.S., Opanasyuk N.M., Danilchenko S.M., Starikov V.V.; **14**(2), 157-163.
- Ivashchenko O.M.** – Optimized calibration of cryogenic silicon thermodiodes – Shwarts Yu.M., Shwarts M.M., Kopko D.P., Sypko M.I.; **14**(4), 399-402.
- Ivon A.I.** – See Chernenko I.M., Mysov O.P., Oleinik O.Yu.; **14**(1), 51-54.
- Izai V.Yu.** – See Studenyak I.P., Stephanovich V.O., Panko V.V., Kúš P., Plecenik A., Zahoran M., Greguš J., Roch T.; **14**(3), 287-293.

J

- Javidi S.** – Influence of Ca²⁺ ions on the habit of KDP crystals – Enayati R., Iraj M., Aliakbari N.; **14**(2), 175-182.

K

- Kalchenko V.I.** – See Kostyukevych K.V., Khristosenko R.V., Shirshov Yu.M., Kostyukevych S.A., Samoylov A.V.; **14**(3), 313-320.
- Kapoor Vinod** – See Rana Ashwani K., Chand Narottam; **14**(2), 203-208.
- Karachevtsev A.V.** – See Balanetska V.O., Marchuk Yu., Ushenko V.O.; **14**(2), 188-194.
- Karpenko A.Ya.** – See Dolgolenko A.P., Druzhinin A.A., Nichkalo S.I., Ostrovsky I.P., Litovchenko P.G., Litovchenko A.P.; **14**(4), 456-460.
- Katerynchuk V.M.** – Sheet resistance and surface topology time dynamics of intrinsic oxide film on InSe crystals – Kovalyuk Z.D.; **14**(1), 106-108.
- Kazantseva Z.I.** – See Dvoynenko M.M., Strelchuk V.V., Kolomys O.F., Bortshagovsky E.G., Venger E.F., Tronc P.; **14**(2), 195-199.
- Khandozhko A.G.** – See Kovalyuk Z.D., Lastivka G.I., Samila A.P.; **14**(2), 164-166.

- Khatsevich I.M.** – See Lisovskyy I.P., Litovchenko V.G., Zlobin S.O., Voitovych M.V., Indutnyi I.Z., Shepeliavy P.E., Kolomys O.F.; **14**(1), 127-129.
- Khatsevich I.M.** – See Oberemok O.S., Litovchenko V.G., Gamov D.V., Popov V.G., Melnik V.P., Gudymenko O.Yo., Nikirin V.A.; **14**(3), 269-272.
- Khristosenko R.V.** – See Kostyukevych K.V., Shirshov Yu.M., Kostyukevych S.A., Samoylov A.V., Kalchenko V.I.; **14**(3), 313-320.
- Khrypunov G.** – The role of copper in bifacial CdTe based solar cells – Meriuts A., Shelest T., Deineko N., Klyui N., Avksentyeva L., Gorbulik V.; **14**(3), 308-312.
- Khrypunov G.S.** – Thin films CdS/CdTe solar cells with different activation processes base layer – Shelest T.N., Li T.N., Meriuts A.V., Kovtun N.A., Makarov A.V., Avksentyeva L.V.; **14**(1), 122-126.
- Kiisk V.** – See Dolgov L., Kravchuk R., Rybak A., Sildos I., Blonsky I.; **14**(3), 325-329.
- Kiselov V.S.** – Simple method for SiC nanowires fabrication – Lytvyn O.S., Yukhymchuk V.O., Belyaev A.E.; **14**(1), 7-11.
- Kladko V.P.** – See Gudymenko O.Yo., Yefanov O.M., Slobodian M.V., Polischuk Yu.S., Krasilnik Z.F., Lobanov D.V., Novikov A.A.; **14**(4), 389-392.
- Klym H.** – Study of nanoporous in humidity-sensitive MgAl₂O₄ ceramics with positron annihilation lifetime spectroscopy; **14**(1), 109-113.
- Klyui N.** – See Khrypunov G., Meriuts A., Shelest T., Deineko N., Avksentyeva L., Gorbulik V.; **14**(3), 308-312.
- Kobeleva O.I.** – Photochromic properties of composite films of thermally irreversible diarylethenes and fulgimides in polytetra-fluoroethylene matrix – Valova T.M., Ait A.O., Barachevsky V.A., Grytsenko K.P., Machulin V.F., Krayushkin M.M.; **14**(4), 441-444.
- Kochelab E.V.** – See Vladimirova T.P., Kyslovs'kyy Ye M., Molodkin V.B., Olikhovskii S.I., Koplak O.V.; **14**(4), 470-477.
- Kolomys O.F.** – See Dvoynenko M.M., Kazantseva Z.I., Strelchuk V.V., Bortshagovsky E.G., Venger E.F., Tronc P.; **14**(2), 195-199.
- Kolomys O.F.** – See Lisovskyy I.P., Litovchenko V.G., Zlobin S.O., Voitovych M.V., Khatsevich I.M., Indutnyi I.Z., Shepeliavy P.E.; **14**(1), 127-129.
- Kominami H.** – See Marchylo O.M., Zavyalova L.V., Nakanishi Y., Belyaev A.E., Svechnikov G.S.; **14**(4), 461-464.
- Konakova R.V.** – See Belyaev A.E., Boltovet N.S., Kudryk Ya.Ya., Sorokin V.M., Sheremet V.N., Shynkarenko V.V.; **14**(4), 465-469.

- Kopko D.P.** – See Ivashchenko O.M., Shwarts Yu.M., Shwarts M.M., Sypko M.I.; **14(4)**, 399-402.
- Koplak O.V.** – See Steblenko L.P., Syvorotka I.I., Kravchenko V.S.; **14(3)**, 334-338.
- Koplak O.V.** – See Vladimirova T.P., Kyslovs'kyy Ye M., Molodkin V.B., Olikhovskii S.I., Kochelab E.V.; **14(4)**, 470-477.
- Kormosh V.V.** – See Kozubovsky V.R., Alyakshev I.P., Lishchenko N.H.; **14(3)**, 330-333.
- Kostyukevych K.V.** – Multi-element gas sensor based on surface plasmon resonance: recognition of alcohols by using calixarene films – Khristosenko R.V., Shirshov Yu.M., Kostyukevych S.A., Samoylov A.V., Kalchenko V.I.; **14(3)**, 313-320.
- Kostyukevych K.V.** – See Kostyukevych S.O., Muravsky L.I., Fitio V.M., Voronyak T.I., Shepelevyi P.E., Moskalenko N.L., Pogoda V.I.; **14(3)**, 350-356.
- Kostyukevych S.A.** – See Kostyukevych K.V., Khristosenko R.V., Shirshov Yu.M., Samoylov A.V., Kalchenko V.I.; **14(3)**, 313-320.
- Kostyukevych S.O.** – The new approach to identification of film reflecting holographic marks – Muravsky L.I., Fitio V.M., Voronyak T.I., Shepelevyi P.E., Kostyukevych K.V., Moskalenko N.L., Pogoda V.I.; **14(3)**, 350-356.
- Kosyachenko L.A.** – Energy band gap and electrical conductivity of $Cd_{1-x}Mn_xTe$ alloys with different manganese content – Rarenko I.M., Aoki T., Sklyarchuk V.M., Maslyanchuk O.L., Yurtsenyuk N.S., Zakharkov Z.I.; **14(4)**, 421-426.
- Kovalchuk O.V.** – Adsorption of ions and thickness dependence of conductivity in liquid crystals; **14(4)**, 452-455.
- Kovalchuk O.V.** – Method and estimation of parameters of dense part of electrical double layer at the interface electrode-solution of the dye in liquid crystal; **14(3)**, 321-324.
- Kovalchuk O.V.** – See Vovk V.E., Gorishnyj M.P., Kovalchuk T.M.; **14(2)**, 256-260.
- Kovalchuk T.M.** – See Vovk V.E., Kovalchuk O.V., Gorishnyj M.P.; **14(2)**, 256-260.
- Kovalyuk Z.D.** – See Brus V.V., Parfenyuk O.A., Vakhnyak N.D.; **14(4)**, 427-431.
- Kovalyuk Z.D.** – See Katerynchuk V.M.; **14(1)**, 106-108.
- Kovalyuk Z.D.** – See Lashkarev G.V. Sichkovskiy V.I., Radchenko M.V., Aleshkevych P., Dmitriev O.I., Butorin P.E., Szymczak R., Slawska-Waniewska A., Nedelko N., Yakiela R., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14(3)**, 263-268.
- Kovalyuk Z.D.** – The electric field gradient asymmetry parameter in InSe – Khandozhko A.G., Lastivka G.I., Samila A.P.; **14(2)**, 164-166.
- Kovtun N.A.** – See Khrypunov G.S., Shelest T.N., Li T.N., Meriuts A.V., Makarov A.V., Avksentyeva L.V.; **14(1)**, 122-126.
- Kozubovsky V.R.** – Sensors for fire gas detectors – Kormosh V.V., Alyakshev I.P., Lishchenko N.H.; **14(3)**, 330-333.
- Krasilnik Z.F.** – See Gudymenko O.Yo., Kladko V.P., Yefanov O.M., Slobodian M.V., Polischuk Yu.S., Lobanov D.V., Novikov A.A.; **14(4)**, 389-392.
- Kravchenko V.S.** – See Steblenko L.P., Koplak O.V., Syvorotka I.I.; **14(3)**, 334-338.
- Kravchuk R.** – See Dolgov L., Rybak A., Kiisk V., Sildos I., Blonskyi I.; **14(3)**, 325-329.
- Kravtsova A.S.** – See Pavlovich I.I., Tomashik Z.F., Stratichuk I.B., Tomashik V.M., Savchuk O.A.; **14(2)**, 200-202.
- Krayushkin M.M.** – See Kobeleva O.I., Valova T.M., Ait A.O., Barachevsky V.A., Grytsenko K.P., Machulin V.F.; **14(4)**, 441-444.
- Krolevec N.M.** – See Sukach A.V., Tetyorkin V.V.; **14(4)**, 416-420.
- Kudryk Ya.Ya.** – See Belyaev A.E., Boltovets N.S., Konakova R.V., Sorokin V.M., Sheremet V.N., Shynkarenko V.V.; **14(4)**, 465-469.
- Kudryk Ya.Ya.** – See Zorenko A.V., Marunenko Yu.V.; **14(4)**, 411-415.
- Kulish M.R.** – Hydrothermal synthesis and properties of titania nanotubes doped with Fe, Ni, Zn, Cd, Mn – Struzhko V.L., Briksa V.P., Murashko A.V., Il'in V.G.; **14(1)**, 21-30.
- Kumar S.** – See Sharma J.; **14(2)**, 152-156.
- Kúš P.** – See Studenjak I.P., Izai V.Yu., Stephanovich V.O., Panko V.V., Plecenik A., Zahoran M., Greguš J., Roch T.; **14(3)**, 287-293.
- Kuzmich A.** – See Burbelo R., Isaiev M.; **14(2)**, 167-169.
- Kuznetsov G.V.** – See Manilov A.I., Skryshevsky V.A., Alekseev S.A.; **14(1)**, 1-6.
- Kyslovs'kyy Ye M.** – See Vladimirova T.P., Molodkin V.B., Olikhovskii S.I., Koplak O.V., Kochelab E.V.; **14(4)**, 470-477.
- Kyutt R.N.** – See Shul'pina I.L., Ratnikov V.V., Prokhorov I.A., Bezbakh I.Zh., Shcheglov M.P.; **14(1)**, 62-70.

L

- Lashkarev G.V.** – Diluted magnetic layered semiconductor InSe:Mn with high Curie temperature – Sichkovskiy V.I., Radchenko M.V., Aleshkevych P., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A., Nedelko N., Yakiela R., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14(3)**, 263-268.
- Lastivka G.I.** – See Kovalyuk Z.D., Khandozhko A.G., Samila A.P.; **14(2)**, 164-166.

- Li T.N.** – See Khrypunov G.S., Shelest T.N., Meriuts A.V., Kovtun N.A., Makarov A.V., Avksentyeva L.V.; **14(1)**, 122-126.
- Lishchenko N.H.** – See Kozubovsky V.R., Kormosh V.V., Alyakshev I.P.; **14(3)**, 330-333.
- Lisovskyy I.P.** – Effect of low-temperature annealing on light-emitting properties of na-Si/SiO_x porous nanocomposite films – Litovchenko V.G., Zlobin S.O., Voitovich M.V., Khatsevich I.M., Indutnyi I.Z., Shepelevyi P.E., Kolomys O.F.; **14(1)**, 127-129.
- Litovchenko A.P.** – See Dolgolenko A.P., Druzhinin A.A., Karpenko A.Ya., Nichkalo S.I., Ostrovsky I.P., Litovchenko P.G.; **14(4)**, 456-460.
- Litovchenko P.G.** – See Dolgolenko A.P., Druzhinin A.A., Karpenko A.Ya., Nichkalo S.I., Ostrovsky I.P., Litovchenko A.P.; **14(4)**, 456-460.
- Litovchenko P.G.** – See Gaidar G.P., Dolgolenko A.P.; **14(2)**, 213-221.
- Litovchenko V.G.** – See Lisovskyy I.P., Zlobin S.O., Voitovich M.V., Khatsevich I.M., Indutnyi I.Z., Shepelevyi P.E., Kolomys O.F.; **14(1)**, 127-129.
- Litovchenko V.G.** – See Oberemok O.S., Gamov D.V., Popov V.G., Melnik V.P., Gudymenko O.Yo., Nikirin V.A., Khatsevich I.M.; **14(3)**, 269-272.
- Lobanov D.V.** – See Gudymenko O.Yo., Kladko V.P., Yefanov O.M., Slobodian M.V., Polischuk Yu.S., Krasilnik Z.F., Novikov A.A.; **14(4)**, 389-392.
- Lopatynska O.** – See Lopatynskyi A., Chegel V.; **14(1)**, 114-121.
- Lopatynskyi A.** – Comparative analysis of response modes for gold nanoparticle biosensor based on localized surface plasmon resonance – Lopatynska O., Chegel V.; **14(1)**, 114-121.
- Lozovski V.** – Can nanoparticles be useful for antiviral therapy? – Lysenko V., Pyatnitsia V., Spivak M.; **14(4)**, 489-491.
- Lysenko V.** – See Lozovski V., Pyatnitsia V., Spivak M.; **14(4)**, 489-491.
- Lysiuk V.O.** – Optical properties of ion implanted thin Ni films on lithium niobate – Staschuk V.S., Androsyuk I.G., Moskalenko N.L.; **14(1)**, 59-61.
- Lysiuk Yu.V.** – See Freik D.M., Yurchyshyn I.K., Potyak V.Yu.; **14(3)**, 344-349.
- Lytvyn O.S.** – See Bratus' O.L., Evtukh A.A., Voitovich M.V., Yukhymchuk V.O.; **14(2)**, 247-255.
- Lytvyn O.S.** – See Kiselov V.S., Yukhymchuk V.O., Belyaev A.E.; **14(1)**, 7-11.
- Lytvyn P.M.** – See Strelchuk V.V., Bryksa V.P., Avramenko K.A., Valakh M.Ya., Pashchenko V.O., Bludov O.M., Deparis C., Morhain C., Tronc P.; **14(1)**, 31-40.
- Lytvyn P.M.** – See Vlasenko N.A., Oleksenko P.F., Mukhlyo M.O., Veligura L.I., Denisova Z.L.; **14(3)**, 339-343.

M

- Machulin V.F.** – See Kobeleva O.I., Valova T.M., Ait A.O., Barachevsky V.A., Grytsenko K.P., Krayushkin M.M.; **14(4)**, 441-444.
- Majlis B.Y.** – See Elgomati H.A., Ahmad I., Salehuddin F., Hamid F.A., Zaharim A., Apte P.R.; **14(2)**, 145-151.
- Makarov A.V.** – See Khrypunov G.S., Shelest T.N., Li T.N., Meriuts A.V., Kovtun N.A., Avksentyeva L.V.; **14(1)**, 122-126.
- Manilov A.I.** – Electrophysical properties of mesoporous silicon free standing films modified with palladium – Skryshevsky V.A., Alekseev S.A., Kuznetsov G.V.; **14(1)**, 1-6.
- Marchenko L.S.** – See Baschenko S.M.; **14(1)**, 77-79.
- Marchuk Yu.** – See Balanetska V.O., Karachevtsev A.V., Ushenko V.O.; **14(2)**, 188-194.
- Marchylo O.M.** – Investigation of luminescent properties inherent to SrTiO₃:Pr³⁺ luminophor with Al impurity – Zavyalova L.V., Nakanishi Y., Kominami H., Belyaev A.E., Svechnikov G.S.; **14(4)**, 461-464.
- Marunenko Yu.V.** – See Zorenko A.V., Kudryk Ya.Ya.; **14(4)**, 411-415.
- Maslyanchuk O.L.** – See Kosyachenko L.A., Rarenko I.M., Aoki T., Sklyarchuk V.M., Yurtsenyuk N.S., Zakharuk Z.I.; **14(4)**, 421-426.
- Melnik V.P.** – See Bunak S.V., Ilchenko V.V., Hatsevych I.M., Romanyuk B.N., Shkavro A.G., Tretyak O.V.; **14(2)**, 241-246.
- Melnik V.P.** – See Oberemok O.S., Litovchenko V.G., Gamov D.V., Popov V.G., Gudymenko O.Yo., Nikirin V.A., Khatsevich I.M.; **14(3)**, 269-272.
- Meriuts A.** – See Khrypunov G., Shelest T., Deineko N., Klyui N., Avksentyeva L., Gorbulik V.; **14(3)**, 308-312.
- Meriuts A.V.** – See Khrypunov G.S., Shelest T.N., Li T.N., Kovtun N.A., Makarov A.V., Avksentyeva L.V.; **14(1)**, 122-126.
- Michailovska K.V.** – See Sopinskyy M.V., Indutnyi I.Z., Shepelevyi P.E., Tkach V.M.; **14(3)**, 273-278.
- Mishinova G.N.** – See Vlaskina S.I., Vlaskin V.I., Rodionov V.E., Svechnikov G.S.; **14(4)**, 432-436.
- Molodkin V.B.** – See Vladimirova T.P., Kyslovs'kyy Ye M., Olikhovskii S.I., Koplak O.V., Kochelab E.V.; **14(4)**, 470-477.
- Morhain C.** – See Strelchuk V.V., Bryksa V.P., Avramenko K.A., Lytvyn P.M., Valakh M.Ya., Pashchenko V.O., Bludov O.M., Deparis C., Tronc P.; **14(1)**, 31-40.
- Moskalenko N.L.** – See Kostyukevych S.O., Muravsky L.I., Fitio V.M., Voronyak T.I.,

- Shepeliavyi P.E., Kostyukevych K.V., Pogoda V.I.; **14**(3), 350-356.
Moskalenko N.L. – See Lysiuk V.O., Staschuk V.S., Androsyuk I.G.; **14**(1), 59-61.
Mukherjee Moumita – See Tripathy P.R., Pati S.P.; **14**(2), 137-144.
Mukhlyo M.O. – See Vlasenko N.A., Oleksenko P.F., Lytvyn P.M., Veligura L.I., Denisova Z.L.; **14**(3), 339-343.
Murashko A.V. – See Kulish M.R., Struzhko V.L., Briksa V.P., Il'in V.G.; **14**(1), 21-30.
Muravsky L.I. – See Kostyukevych S.O., Fitio V.M., Voronyak T.I., Shepeliavyi P.E., Kostyukevych K.V., Moskalenko N.L., Pogoda V.I.; **14**(3), 350-356.
Mysov O.P. – See Chernenko I.M., Oleinik O.Yu., Ivon A.I.; **14**(1), 51-54.

N

- Nakanishi Y.** – See Marchylo O.M., Zavyalova L.V., Kominami H., Belyaev A.E., Svechnikov G.S.; **14**(4), 461-464.
Nedelko N. – See Lashkarev G.V., Sichkovskyi V.I., Radchenko M.V., Aleshkevych P., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A., Yakiela R., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14**(3), 263-268.
Nichkalo S.I. – See Dolgolenko A.P., Druzhinin A.A., Karpenko A.Ya., Ostrovsky I.P., Litovchenko P.G., Litovchenko A.P.; **14**(4), 456-460.
Nikirin V.A. – See Oberemok O.S., Litovchenko V.G., Gamov D.V., Popov V.G., Melnik V.P., Gudymenko O.Yo., Khatsevich I.M.; **14**(3), 269-272.
Novikov A.A. – See Gudymenko O.Yo., Kladko V.P., Yefanov O.M., Slobodian M.V., Polischuk Yu.S., Krasilnik Z.F., Lobanov D.V.; **14**(4), 389-392.

O

- Oberemok O.S.** – Formation of silicon nanoclusters in buried ultra-thin oxide layers – Litovchenko V.G., Gamov D.V., Popov V.G., Melnik V.P., Gudymenko O.Yo., Nikirin V.A., Khatsevich I.M.; **14**(3), 269-272.
Olar O.I. – See Ushenko Yu.A., Dubolazov A.V., Balanetskaya V.O., Unguryan V.P., Oleinichenko N.I., Zabolotna B.P.; **14**(1), 98-105.
Oleinichenko N.I. – See Ushenko Yu.A., Olar O.I., Dubolazov A.V., Balanetskaya V.O., Unguryan V.P., Zabolotna B.P.; **14**(1), 98-105.
Oleinik O.Yu. – See Chernenko I.M., Mysov O.P., Ivon A.I.; **14**(1), 51-54.

- Oleksenko P.F.** – See Vlasenko N.A., Mukhlyo M.O., Lytvyn P.M., Veligura L.I., Denisova Z.L.; **14**(3), 339-343.
Olikhovskii S.I. – See Vladimirova T.P., Kyslovs'kyj Ye M., Molodkin V.B., Koplak O.V., Kochelab E.V.; **14**(4), 470-477.
Opanasyuk A.S. – See Ivashchenko M.M., Opanasyuk N.M., Danilchenko S.M., Starikov V.V.; **14**(2), 157-163.
Opanasyuk N.M. – See Ivashchenko M.M., Opanasyuk A.S., Danilchenko S.M., Starikov V.V.; **14**(2), 157-163.
Ostrovsky I.P. – See Dolgolenko A.P., Druzhinin A.A., Karpenko A.Ya., Nichkalo S.I., Litovchenko P.G., Litovchenko A.P.; **14**(4), 456-460.

P

- Panko V.V.** – See Studenyak I.P., Izai V.Yu., Stephanovich V.O., Kúš P., Plecenik A., Zahoran M., Greguš J., Roch T.; **14**(3), 287-293.
Parfenyuk O.A. – See Brus V.V., Kovalyuk Z.D., Vakhnyak N.D.; **14**(4), 427-431.
Pashchenko V.O. – See Strelchuk V.V., Bryksa V.P., Avramenko K.A., Lytvyn P.M., Valakh M.Ya., Bludov O.M., Deparis C., Morhain C., Tronc P.; **14**(1), 31-40.
Pati S.P. – See Tripathy P.R., Mukherjee Moumita; **14**(2), 137-144.
Pavlovich I.I. – Chemical-dynamic polishing of semiconductor materials based on Bi and Sb chalcogenides by using $\text{HNO}_3\text{-HCl}$ solutions – Tomashik Z.F., Stratichuk I.B., Tomashik V.M., Savchuk O.A., Kravtsova A.S.; **14**(2), 200-202.
Perevertailo V.L. – See Dobrovolskiy Yu.G., Shabashkevich B.G.; **14**(3), 298-301.
Pipa V.I. – Electromagnetic field quantization in planar absorbing heterostructures; **14**(1), 91-97.
Plecenik A. – See Studenyak I.P., Izai V.Yu., Stephanovich V.O., Panko V.V., Kúš P., Zahoran M., Greguš J., Roch T.; **14**(3), 287-293.
Plyaka S.N. – See Bochkova T.M.; **14**(2), 170-174.
Pogoda V.I. – See Kostyukevych S.O., Muravsky L.I., Fitio V.M., Voronyak T.I., Shepeliavyi P.E., Kostyukevych K.V., Moskalenko N.L.; **14**(3), 350-356.
Polischuk Yu.S. – See Gudymenko O.Yo., Kladko V.P., Yefanov O.M., Slobodian M.V., Krasilnik Z.F., Lobanov D.V., Novikov A.A.; **14**(4), 389-392.
Popov V.G. – See Oberemok O.S., Litovchenko V.G., Gamov D.V., Melnik V.P., Gudymenko O.Yo., Nikirin V.A., Khatsevich I.M.; **14**(3), 269-272.

- Poroshin V.M.** – See Gudenko Yu.M., Vainberg V.V., Tulupenko V.M.; **14(3)**, 375-379.
- Potyak V.Yu.** – See Freik D.M., Yurchyshyn I.K., Lysiuk Yu.V.; **14(3)**, 344-349.
- Prokhorov I.A.** – See Shul'pina I.L., Kyutt R.N., Ratnikov V.V., Bezbakh I.Zh., Shcheglov M.P.; **14(1)**, 62-70.
- Pyatnitsia V.** – See Lozovski V., Lysenko V., Spivak M.; **14(4)**, 489-491.

R

- Radchenko M.V.** – See Lashkarev G.V. Sichkovskyi V.I., Aleshkevych P., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A., Nedelko N., Yakiela R., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14(3)**, 263-268.
- Rana Ashwani K.** – Impact of sidewall spacer on gate leakage behavior of nano-scale MOSFETs – Chand Narottam, Kapoor Vinod; **14(2)**, 203-208.
- Rarenko I.M.** – See Kosyachenko L.A., Aoki T., Sklyarchuk V.M., Maslyanchuk O.L., Yurtsenyuk N.S., Zakharuk Z.I.; **14(4)**, 421-426.
- Ratnikov V.V.** – See Shul'pina I.L., Kyutt R.N., Prokhorov I.A., Bezbakh I.Zh., Shcheglov M.P.; **14(1)**, 62-70.
- Roch T.** – See Studenyak I.P., Izai V.Yu., Stephanovich V.O., Panko V.V., Kúš P., Plecenik A., Zahoran M., Greguš J.; **14(3)**, 287-293.
- Rodionov V.E.** – See Vlaskina S.I., Mishinova G.N., Vlaskin V.I., Svechnikov G.S.; **14(4)**, 432-436.
- Romanyuk B.N.** – See Bunak S.V., Ilchenko V.V., Melnik V.P., Hatsevych I.M., Shkavro A.G., Tretyak O.V.; **14(2)**, 241-246.
- Rudnev I.A.** – See Borblik V.L., Shwarts Yu.M., Shwarts M.M.; **14(1)**, 88-90.
- Rybák A.** – See Dolgov L., Kravchuk R., Kiisk V., Sildos I., Blonskyi I.; **14(3)**, 325-329.

S

- Sakhno M.V.** – Simulated properties of printed antennas on silicon substrates for THz/sub-THz arrays – Gumenjuk-Sichevska J.V., Sizov F.F.; **14(1)**, 55-58.
- Salehuddin F.** – See Elgomati H.A., Ahmad I., Hamid F.A., Zaharim A., Majlis B.Y., Apte P.R.; **14(2)**, 145-151.
- Salkov E.A.** – An intrinsic physical content of “single photon power” – $(hv \cdot \Delta v)$ – Svechnikov G.S.; **14(1)**, 12-20.
- Samila A.P.** – See Kovalyuk Z.D., Khandozhko A.G., Lastivka G.I.; **14(2)**, 164-166.
- Samoylov A.V.** – See Kostyukevych K.V., Khristosenko R.V., Shirshov Yu.M.,

- Kostyukevych S.A., Kalchenko V.I.; **14(3)**, 313-320.
- Savchuk O.A.** – See Pavlovich I.I., Tomashik Z.F., Stratychuk I.B., Tomashik V.M., Kravtsova A.S.; **14(2)**, 200-202.
- Severin V.S.** – Influence of polarization of conduction electrons in semiconductor on their light absorption; **14(4)**, 445-451.
- Severin V.S.** – Influence of polarization of free-electron system in semiconductor on the position of minimum in plasma light reflection; **14(2)**, 170-174.
- Shabashkevich B.G.** – See Dobrovolskiy Yu.G., Perevertailo V.L.; **14(3)**, 298-301.
- Sharma J.** – Role of Sb additive in the dielectric properties of $Se_{90}In_{10}$ and $Se_{75}In_{25}$ glassy alloys – Kumar S.; **14(2)**, 152-156.
- Shcheglov M.P.** – See Shul'pina I.L., Kyutt R.N., Ratnikov V.V., Prokhorov I.A., Bezbakh I.Zh.; **14(1)**, 62-70.
- Shelest T.** – See Khrypunov G., Meriuts A., Deineko N., Klyui N., Avksentyeva L., Gorbulik V.; **14(3)**, 308-312.
- Shelest T.N.** – See Khrypunov G.S., Li T.N., Meriuts A.V., Kovtun N.A., Makarov A.V., Avksentyeva L.V.; **14(1)**, 122-126.
- Shepeliavy P.E.** – See Sopinskyy M.V., Indutnyi I.Z., Michailovska K.V., Tkach V.M.; **14(3)**, 273-278.
- Shepeliavyi P.E.** – See Kostyukevych S.O., Muravsky L.I., Fitio V.M., Voronyak T.I., Kostyukevych K.V., Moskalenko N.L., Pogoda V.I.; **14(3)**, 350-356.
- Shepeliavyi P.E.** – See Lisovskyy I.P., Litovchenko V.G., Zlobin S.O., Voitovych M.V., Khatsevich I.M., Indutnyi I.Z., Kolomys O.F.; **14(1)**, 127-129.
- Sheremet V.N.** – See Belyaev A.E., Boltovets N.S., Konakova R.V., Kudryk Ya.Ya., Sorokin V.M., Shynkarenko V.V.; **14(4)**, 465-469.
- Shirshov Yu.M.** – See Kostyukevych K.V., Khristosenko R.V., Kostyukevych S.A., Samoylov A.V., Kalchenko V.I.; **14(3)**, 313-320.
- Shkavro A.G.** – See Bunak S.V., Ilchenko V.V., Melnik V.P., Hatsevych I.M., Romanyuk B.N., Tretyak O.V.; **14(2)**, 241-246.
- Shul'pina I.L.** – X-ray study of dopant state in highly doped semiconductor single crystals – Kyutt R.N., Ratnikov V.V., Prokhorov I.A., Bezbakh I.Zh., Shcheglov M.P.; **14(1)**, 62-70.
- Shwarts M.M.** – See Borblik V.L., Rudnev I.A., Shwarts Yu.M.; **14(1)**, 88-90.
- Shwarts M.M.** – See Ivashchenko O.M., Shwarts Yu.M., Kopko D.P., Sypko M.I.; **14(4)**, 399-402.
- Shwarts Yu.M.** – See Borblik V.L., Rudnev I.A., Shwarts M.M.; **14(1)**, 88-90.
- Shwarts Yu.M.** – See Ivashchenko O.M., Shwarts M.M., Kopko D.P., Sypko M.I.; **14(4)**, 399-402.

- Shynkarenko V.V.** – See Belyaev A.E., Boltovets N.S., Konakova R.V., Kudryk Ya.Ya., Sorokin V.M., Sheremet V.N.; **14(4)**, 465-469.
- Sichkovskyi V.I.** – See Lashkarev G.V. Radchenko M.V., Aleshkevych P., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A., Nedelko N., Yakiela R., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14(3)**, 263-268.
- Sildos I.** – See Dolgov L., Kravchuk R., Rybak A., Kiisk V., Blonskyi I.; **14(3)**, 325-329.
- Sizov F.F.** – See Sakhno M.V., Gumenjuk-Sichevska J.V.; **14(1)**, 55-58.
- Sklyarchuk V.M.** – See Kosyachenko L.A., Rarenko I.M., Aoki T., Maslyanchuk O.L., Yurtsenyuk N.S., Zakhark Z.I.; **14(4)**, 421-426.
- Skryshevsky V.A.** – See Manilov A.I., Alekseev S.A., Kuznetsov G.V.; **14(1)**, 1-6.
- Slawska-Waniewska A.** – See Lashkarev G.V. Sichkovskyi V.I., Radchenko M.V., Aleshkevych P., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Szymczak R., Nedelko N., Yakiela R., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14(3)**, 263-268.
- Slobodian M.V.** – See Gudymenko O.Yo., Kladko V.P., Yefanov O.M., Polischuk Yu.S., Krasilnik Z.F., Lobanov D.V., Novikov A.A.; **14(4)**, 389-392.
- Sopinskyy M.V.** – Polarization conversion effect in obliquely deposited SiO_x films – Indutnyi I.Z., Michailovska K.V., Shepeliavy P.E., Tkach V.M.; **14(3)**, 273-278.
- Sorokin V.M.** – See Belyaev A.E., Boltovets N.S., Konakova R.V., Kudryk Ya.Ya., Sheremet V.N., Shynkarenko V.V.; **14(4)**, 465-469.
- Spivak M.** – See Lozovski V., Lysenko V., Pyatnitsia V.; **14(4)**, 489-491.
- Starikov V.V.** – See Ivashchenko M.M., Opanasyuk A.S., Opanasyuk N.M., Danilchenko S.M.; **14(2)**, 157-163.
- Staschuk V.S.** – See Lysiuk V.O., Androsyuk I.G., Moskalenko N.L.; **14(1)**, 59-61.
- Steblenko L.P.** – Effect of magnetic field on the reconstruction of the defect-impurity state and cathodoluminescence in Si/SiO₂ structure – Koplak O.V., Syvorotka I.I., Kravchenko V.S.; **14(3)**, 334-338.
- Stephanovich V.O.** – See Studenyak I.P., Izai V.Yu., Panko V.V., Kúš P., Plecenik A., Zahoran M., Greguš J., Roch T.; **14(3)**, 287-293.
- Stratiychuk I.B.** – See Pavlovich I.I., Tomashik Z.F., Tomashik V.M., Savchuk O.A., Kravtsova A.S.; **14(2)**, 200-202.
- Strelchuk V.V.** – Ferromagnetism in Co-doped ZnO films grown by molecular beam epitaxy: magnetic, electrical and microstructural studies – Bryksa V.P., Avramenko K.A., Lytvyn P.M., Valakh M.Ya., Pashchenko V.O., Bludov O.M., C. Deparis, Morhain C., Trone P.; **14(1)**, 31-40.

Strelchuk V.V. – See Dvoynenko M.M., Kazantseva Z.I., Kolomys O.F., Bortshagovsky E.G., Venger E.F., Tronc P.; **14(2)**, 195-199.

Struzhko V.L. – See Kulish M.R. Briksa V.P., Murashko A.V., Il'in V.G.; **14(1)**, 21-30.

Studenyak I.P. – Optical absorption edge and luminescence in phosphorous-implanted Cu₆PS₅X (X = I, Br) single crystals – Izai V.Yu., Stephanovich V.O., Panko V.V., Kúš P., Plecenik A., Zahoran M., Greguš J., Roch T.; **14(3)**, 287-293.

Sukach A.V. – Tunneling current via dislocations in InAs and InSb infrared photodiodes – Tetyorkin V.V., Krolevec N.M.; **14(4)**, 416-420.

Svechnikov G.S. – See Marchylo O.M., Zavyalova L.V., Nakanishi Y., Kominami H., Belyaev A.E.; **14(4)**, 461-464.

Svechnikov G.S. – See Salkov E.A.; **14(1)**, 12-20.

Svechnikov G.S. – See Vlaskina S.I., Mishinova G.N., Vlaskin V.I., Rodionov V.E.; **14(4)**, 432-436.

Sypko M.I. – See Ivashchenko O.M., Shwarts Yu.M., Shwarts M.M., Kopko D.P.; **14(4)**, 399-402.

Syvorotka I.I. – See Steblenko L.P., Koplak O.V., Kravchenko V.S.; **14(3)**, 334-338.

Szymczak R. – See Lashkarev G.V. Sichkovskyi V.I., Radchenko M.V., Aleshkevych P., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Slawska-Waniewska A., Nedelko N., Yakiela R., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14(3)**, 263-268.

T

Taghiyev T.B. – Photoconductivity and photoluminescence features of γ -irradiated GaS_{0.75}Se_{0.25}(Er) single crystals; **14(3)**, 362-364.

Telenga O.Yu. – See Zabolotna N.I., Balanetska V.O., Ushenko V.O.; **14(2)**, 228-236.

Tetyorkin V.V. – See Sukach A.V., Krolevec N.M.; **14(4)**, 416-420.

Tkach V.M. – See Sopinskyy M.V., Indutnyi I.Z., Michailovska K.V., Shepeliavy P.E.; **14(3)**, 273-278.

Tomashik V.M. – See Pavlovich I.I., Tomashik Z.F., Stratiychuk I.B., Savchuk O.A., Kravtsova A.S.; **14(2)**, 200-202.

Tomashik Z.F. – See Pavlovich I.I., Stratiychuk I.B., Tomashik V.M., Savchuk O.A., Kravtsova A.S.; **14(2)**, 200-202.

Tret'yak O.V. – See Bunak S.V., Ilchenko V.V., Melnik V.P., Hatsevych I.M., Romanyuk B.N., Shkavro A.G.; **14(2)**, 241-246.

Tripathy P.R. – Dynamic properties and avalanche noise analysis of 4H-SiC over wz-GaN based IMPATTs at mm-wave window frequency – Mukherjee Moumita, Pati S.P.; **14(2)**, 137-144.

Tronc P. – See Dvoynenko M.M., Kazantseva Z.I., Strelchuk V.V., Kolomys O.F., Bortshagovsky E.G., Venger E.F.; **14(2)**, 195-199.

Tronc P. – See Strelchuk V.V., Bryksa V.P., Avramenko K.A., Lytvyn P.M., Valakh M.Ya., Pashchenko V.O., Bludov O.M., Deparis C., Morhain C.; **14(1)**, 31-40.

Tulupenko V.M. – See Gudenko Yu.M., Vainberg V.V., Poroshin V.M.; **14(3)**, 375-379.

U

Unguryan V.P. – See Ushenko Yu.A., Olar O.I., Dubolazov A.V., Balanetskaya V.O., Oleinichenko N.I., Zabolotna B.P.; **14(1)**, 98-105.

Ushenko O.G. – Jones-matrix diagnostics of the structure and classification of optical properties inherent to birefringent polycrystalline networks of human biological tissues – Balanetska V.O., Zabolotna N.I.; **14(4)**, 403-410.

Ushenko V.O. – See Balanetska V.O., Marchuk Yu., Karachevtsev A.V.; **14(2)**, 188-194.

Ushenko V.O. – See Zabolotna N.I., Balanetska V.O., Telenga O.Yu.; **14(2)**, 228-236.

Ushenko Yu.A. – Degree of local depolarization determined for fields of laser radiation scattered by multilayer birefringent networks of protein crystals – Angelsky A.P.; **14(1)**, 41-50.

Ushenko Yu.A. – Mueller-matrix diagnostics of optical properties inherent to polycrystalline networks of human blood plasma – Olar O.I., Dubolazov A.V., Balanetskaya V.O., Unguryan V.P., Oleinichenko N.I., Zabolotna B.P.; **14(1)**, 98-105.

Ushenko Yu.O. – Jones-matrix images corresponding to networks of biological crystals for diagnostics and classification of their optical properties – Balanetska V.O., Angelsky O.P.; **14(3)**, 365-374.

V

Vainberg V.V. – See Gudenko Yu.M., Poroshin V.M., Tulupenko V.M.; **14(3)**, 375-379.

Vakhnyak N.D. – See Brus V.V., Kovalyuk Z.D., Parfenyuk O.A.; **14(4)**, 427-431.

Valakh M.Ya. – See Strelchuk V.V., Bryksa V.P., Avramenko K.A., Lytvyn P.M., Pashchenko V.O., Bludov O.M., Deparis C., Morhain C., Tronc P.; **14(1)**, 31-40.

Valova T.M. – See Kobeleva O.I., Ait A.O., Barachevsky V.A., Grytsenko K.P., Machulin V.F., Krayushkin M.M.; **14(4)**, 441-444.

Veligura L.I. – See Vlasenko N.A., Oleksenko P.F., Mukhlyo M.O., Lytvyn P.M., Denisova Z.L.; **14(3)**, 339-343.

Venger E.F. – See Dvoynenko M.M., Kazantseva Z.I., Strelchuk V.V., Kolomys O.F., Bortshagovsky E.G., Tronc P.; **14(2)**, 195-199.

Vladimirova T.P. – Transformations of microdefect structure in silicon crystals under the influence of weak magnetic field – Kyslovs'kyy Ye M., Molodkin V.B., Olikhovskii S.I., Koplak O.V., Kochelab E.V.; **14(4)**, 470-477.

Vlasenko N.A. – See Laser oscillation in Cr²⁺:ZnS waveguide thin-film structures under electrical pumping with impact excitation mechanism – Oleksenko P.F., Mukhlyo M.O., Lytvyn P.M., Veligura L.I., Denisova Z.L.; **14(3)**, 339-343.

Vlaskin V.I. – See Vlaskina S.I., Mishinova G.N., Rodionov V.E., Svechnikov G.S.; **14(4)**, 432-436.

Vlaskina S.I. – 3C-6H transformation in heated cubic silicon carbide 3C-SiC – Mishinova G.N., Vlaskin V.I., Rodionov V.E., Svechnikov G.S.; **14(4)**, 432-436.

Voitovych M.V. – See Bratus' O.L., Evtukh A.A., Lytvyn O.S., Yukhymchuk V.O.; **14(2)**, 247-255.

Voitovych M.V. – See Lisovskyy I.P., Litovchenko V.G., Zlobin S.O., Khatsevich I.M., Indutnyy I.Z., Shepeliavyi P.E., Kolomys O.F.; **14(1)**, 127-129.

Veronyak T.I. – See Kostyukevych S.O., Muravsky L.I., Fitio V.M., Shepeliavyi P.E., Kostyukevych K.V., Moskalenko N.L., Pogoda V.I.; **14(3)**, 350-356.

Vovk V.E. – Dielectric and electro-optical properties of solutions of chemically modified fullerene C60 in nematic liquid crystal – Kovalchuk O.V., Gorishnyj M.P., Kovalchuk T.M.; **14(2)**, 256-260.

Y

Yakiela R. – See Lashkarev G.V., Sichkovskiy V.I., Radchenko M.V., Aleshkevych P., Dmitriev O.I., Butorin P.E., Kovalyuk Z.D., Szymczak R., Slawska-Waniewska A., Nedelko N., Balagurov A.M., Beskrovnyy A.I., Dobrowolski W.; **14(3)**, 263-268.

Yefanov O.M. – See Gudymenko O.Yo., Kladko V.P., Slobodian M.V., Polischuk Yu.S., Krasilnik Z.F., Lobanov D.V., Novikov A.A.; **14(4)**, 389-392.

Yukhymchuk V.O. – See Kiselov V.S., Lytvyn O.S., Belyaev A.E.; **14(1)**, 7-11.

Yukhymchuk V.O. – See Bratus' O.L., Evtukh A.A., Lytvyn O.S., Voitovych M.V.; **14(2)**, 247-255.

Yurchyshyn I.K. – See Freik D.M., Potyak V.Yu., Lysiuk Yu.V.; **14(3)**, 344-349.

Yurtsenyuk N.S. – See Kosyachenko L.A., Rarenko I.M., Aoki T., Sklyarchuk V.M., Maslyanchuk O.L., Zakhruk Z.I.; **14(4)**, 421-426.

Z

- Zabolotna N.I.** – See Ushenko Yu.A., Olar O.I., Dubolazov A.V., Balanetskaya V.O., Unguryan V.P., Oleinichenko N.I.; **14(1)**, 98-105.
- Zabolotna N.I.** – See Ushenko O.G., Balanetska V.O.; **14(4)**, 403-410.
- Zabolotna N.I.** – Wavelet analysis of Jones-matrix images corresponding to polycrystalline networks of biological crystals in diagnostics of tuberculosis – Balanetska V.O., Telenga O.Yu., Ushenko V.O.; **14(2)**, 228-236.
- Zaharim A.** – See Elgomati H.A., Ahmad I., Salehuddin F., Hamid F.A., Majlis B.Y., Apte P.R.; **14(2)**, 145-151.
- Zahoran M.** – See Studenyak I.P., Izai V.Yu., Stephanovich V.O., Panko V.V., Kúš P., Plecenik A., Greguš J., Roch T.; **14(3)**, 287-293.

- Zakharuk Z.I.** – See Kosyachenko L.A., Rarenko I.M., Aoki T., Sklyarchuk V.M., Maslyanchuk O.L., Yurtseyuk N.S.; **14(4)**, 421-426.
- Zavyalova L.V.** – See Marchylo O.M., Nakanishi Y., Kominami H., Belyaev A.E., Svechnikov G.S.; **14(4)**, 461-464.
- Zien M.** – See Amer H.H., Elkordy M., Dahshan A., Elshamy R.A.; **14(3)**, 302-307.
- Zlobin S.O.** – See Lisovskyy I.P., Litovchenko V.G., Voitovych M.V., Khatsevich I.M., Indutnyy I.Z., Shepeliayyi P.E., Kolomys O.F.; **14(1)**, 127-129.
- Zorenko A.V.** – Development and investigation of microwave radiation sources and detector sections using SBDs within the 220–400 GHz frequency range – Kudryk Ya.Ya., Marunenko Yu.V.; **14(4)**, 411-415.